

Test Report issued under the responsibility of:



TEST REPORT IEC 60269-1 Low-voltage fuses

Part 1: General requirements

Report Number.....: 03601-A-16CB0076-S-A

Date of issue.....: 2016-09-12

Total number of pages 37

Applicant's name: Zhejiang Tengen Electrics Co., Ltd.

Address.....: Tengen Industry Zone, Liushi Town, Yueqing City, Zhejiang

Province.

Test specification:

Standard: IEC 60269-1:2006 (Fourth edition)+ A1:2009

Test procedure: CB Scheme

Non-standard test

method....:

N/A

Test Report Form No. IEC60269 1B

Test Report Form(s) Originator: EZU

Master TRF: Dated 2010-08

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Test item description: Fuse-links for the protection of semiconductor devices

Trade Mark.....: /

Manufacturer: Zhejiang Tengen Electrics Co., Ltd.

Model/Type reference: NHZ1-00, NHZ1-00S

Ratings.....: Un: DC80V,

In: 10A,16A,20A,25A,32A,40A,50A,63A,80A,100A,125A, 160A,200A,250A,300A,315A,350A,400A,500A,600A,

Rated breaking capacityI1: 25kA,

Breaking range and utilization category: gS

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Testing procedure and testing location:			
	CB Testing Laboratory:	Suzhou Electrical Apparatus Science Research Institute Stock Co., Ltd.(EETI)	
Testing location/ address:		No.7 Yonghe Street; Binhe Road, New District, Suzhou, China	
	Associated CB Laboratory:	***	各田土山各
Testing location/ address:		M. 4711-	
	Tested by (name + signature):	Wang Wei	112
	Approved by (name + signature):	Hu Delin	胡凌窟
	Testing procedure: TMP		1 0/11/2
Test	ing location/ address:		
	Tested by (name + signature):		
	Approved by (name + signature):		
	Testing procedure: WMT		
Testing location/ address:			
	Tested by (name + signature):		
	Witnessed by (name + signature) .:		
	Approved by (name + signature):		
	Testing procedure: SMT		
Test	ing location/ address:		
	Tested by (name + signature):		
	Approved by (name + signature):		
	Supervised by (name + signature):		
	Testing procedure: RMT		
Testing location/ address:			
	Tested by (name + signature):		
	Approved by (name + signature):		
	Supervised by (name + signature):		